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SPC-F005.DWG

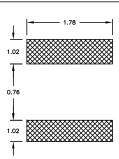
	REVISIONS			DOC. NO. SPC-F005 * Effective: 7/8/02 * DCP N						
DCP #	REV	DESCRIPTION	DRAWN	DATE	CHECKD DATE		APPRVD	DATE		
2048	Α	RELEASED	JN	05/21/09	JWM	05/21/09	JWM	05/21/09		



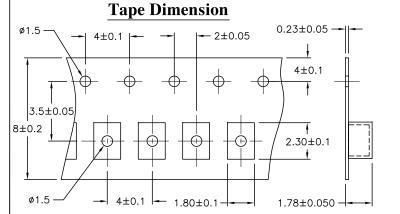
Features:

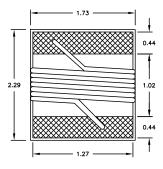
- Wire wound ceramic construction provide high SRF
- Ultra-compact inductors provide exceptional Q values
- Low profile, high current are available
- Miniature SMD chip inductor for fully autmated assembly
- Outstanding endurance from Pull-up force, mechanical shock and pressure
- tighter tolerance down to ±2%

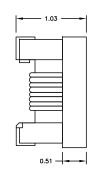
Recommended Pad Layout











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CONDITIONS OF USE ARE BEYOND OUR CONTROL, THE
USER SHALL DETERMINE THE SUITABILITY OF THE PRODUCT
FOR THE INTENDED USE AND ASSUME ALL RISK AND
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UNLESS OTHERWISE
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TOLERANCES:

DRAWN BY:	DATE:
Jason Nash	05/21/09
CHECKED BY:	DATE:
JWM	05/21/09
APPROVED BY:	DATE:
JWM	05/21/09

09	DRAW	ING TITLE: Wire Wound Chip	Inductor — Case siz	ze 080	5 (Low P	rofile)	
	SIZE	DWG. NO.		ELEC	FRONIC FIL	.E	REV
9	Α	Ta-	-1129	Ta	-1129.	.DWG	Α
)9	SCAL	E: NTS	U.O.M.: Millimeters		SHEET:	1 OF	3



Mfr PN	Inductance	Inductance Tolerance	DC Resistance Max	DC Current Rating	Self Resonant Frequency	Package	Q Factor	Test Frequency
MCWL05JTL10N	10nH	± 5%	0.08ohm	800mA	3.30MHz	805	Q Factor:55	250MHz
MCWL05JTL15N	15nH	± 5%	0.10ohm	800mA	2.95MHz	805	Q Factor:50	250MHz
MCWL05JTL22N	22nH	± 5%	0.15ohm	800mA	2.90MHz	805	Q Factor:50	250MHz
MCWL05JTL33N	33nH	± 5%	0.28ohm	600mA	2.35MHz	805	Q Factor:50	250MHz
MCWL05JTL47N	47nH	± 5%	0.39ohm	600mA	2.00MHz	805	Q Factor:50	200MHz
MCWL05JTL68N	68nH	± 5%	0.40ohm	500mA	1.50MHz	805	Q Factor:50	200MHz
MCWL05JTLR10	100nH	± 5%	0.64ohm	400mA	1.20MHz	805	Q Factor:50	150MHz

Mechanical Performance

No.	Item	Specification	Test Methods				
1	Vibration Test	Appearance: No damage L change: within ±5% Q change: within ±10%	Test device shall be soldered on the substrate Oscillation Frequency: 10 to 55 to 10Hz for 1min Amplitude: 1.5mm Time: 2hrs for each axis (X, Y &Z), total 6hrs				
2	Resistance to Soldering-Heat	Q Change, Within 210%	Solder Temperature: 270±5°C Immersion Time: 10±2sec				
3	Component Adhesion (Push Test)						
4	Drop Test	No damage	Dropping chip by each side and each corner. Drop 10 times in total Drop height:100cm Drop weight:125g				
5	Solderability Test	90% covered with solder.	Inductor shall be dipped in a melted solder bath at 245±5°C for 3 seconds.				
6	Resistance to Solvent Test No damage on appearance and marking.		MIL-STD202F, Method 215D				

Electrical Performance Test

No.	ltem .	Specification	Test Method
1	Inductance		HP4291B
2	Q		HP4291B
3	SRF	Refer to standard electrical	HP8753D
4	DC Resistance RDC	characteristic spec.	Micro-Ohm meter (Gom-801G)
5	Rated Current IDC		Applied the current to coils, The inductance change should be less than 10% to initial value
6	Over Load Test	Inductors shall have no evidence of electrical and mechanical damage	Applied 2 times of rated allowed DC current to inductor for a period of 5 minute
7	Withstanding Voltage Test	Inductors shall be no evidence of electrical and mechanical damage.	AC voltage of 500 VAC applied between inductors terminal and case for 1 minute.
8	9		100 VDC applied between inductor terminal and case

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SPC-F005.DWG D00	OC. NO. SPC-F005 * Effective: 7/8/02 * DCP No: 1398	SCALE	: NTS	U.O.M.: INCHES [mm]		SHEET: 2	OF 3	\neg



Climatic Test

No.	ltem	Specification	Test Method				
1	Temperature Characteristic		-40°C +125°C				
2	Humidity Test	F T	Temperature: 40±2°C Relative Humidity: 90~95% Time: 96hrs±2hrs Measured after exposure in the room condition for 2hrs Temperature: -40±2°C Time: 96±2hrs Inductors are tested after 1 hour at room temperature				
3	Low Temperature Storage Test	Appearance: No damage L change: within ±10%					
4	Thermal Shock Test	Q change: within ±20%	One cycle: Step Temperature Time (min) 1 -25±3 30 2 25±2 15 3 125±3 30 4 25±2 15 Total: 5 cycles				
5	High Temperature Storage Test		Temperature:125±2 Time: 96±2hrs Measured after exposure in the room condition for 1hr				
6	High Temperature Load Life Test	There should be no evidence of	Temperature:85±2 Time:1000±12hrs Load: Allowed DC current				
7	Humidity Load Life	short of open circuit.	Temperature: 40±2C Relative Humidity: 90~95% Time: 1000±12hrs Load: Allowed DC current				

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